

Search Notes

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Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

CLARK ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	6/21/2006	CH
455	403	6/21/2006	CH

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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